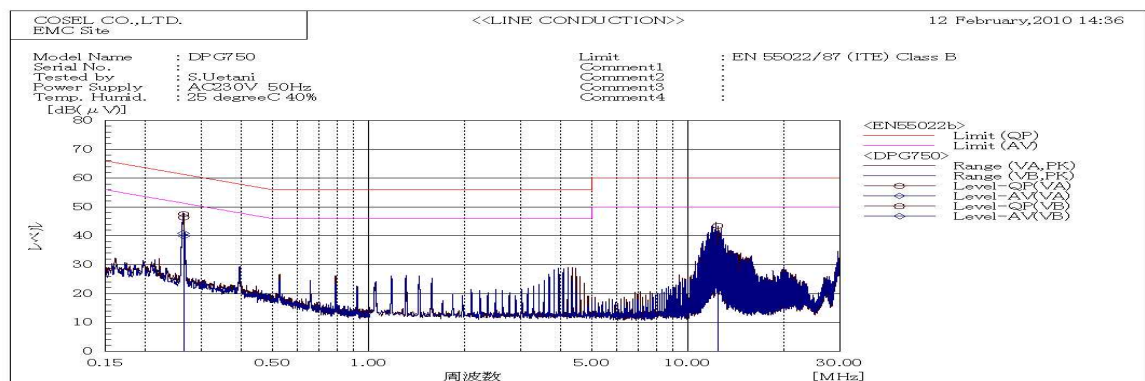
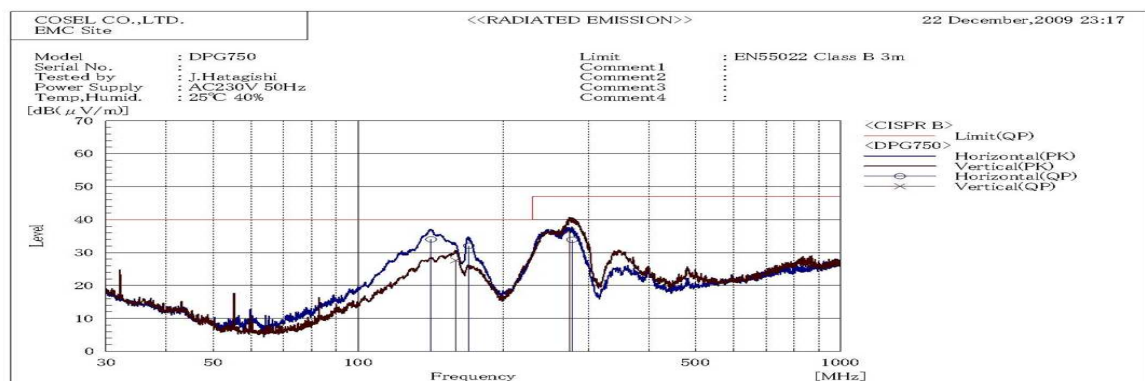


DATA SHEET

Model	DPG750	Date	09-Mar-10
Test	EMI	Temp.	25 degreeC
	Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Uetani



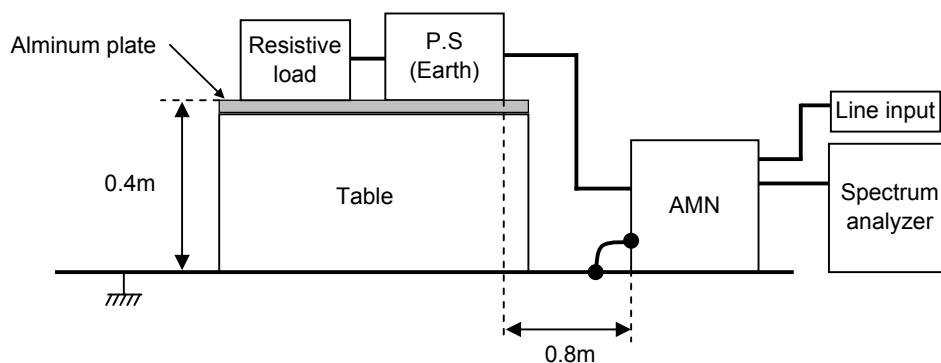
Frequency MHz	Harm	Line Phase	Reading dD(uV)		Factor dD	Level dD(uV)		Limit dD(uV)		Margin dD		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.26105		VA	36.3	29.8	10.1	46.4	39.9	61.3	51.3	14.9	11.1	Pass	
0.26394		VB	37.6	30.9	10	47.6	40.9	61.3	51.3	13.7	10.4	Pass	
12.4021		VB	32.8	26.1	10.7	43.5	36.8	60	50	16.5	13.2	Pass	



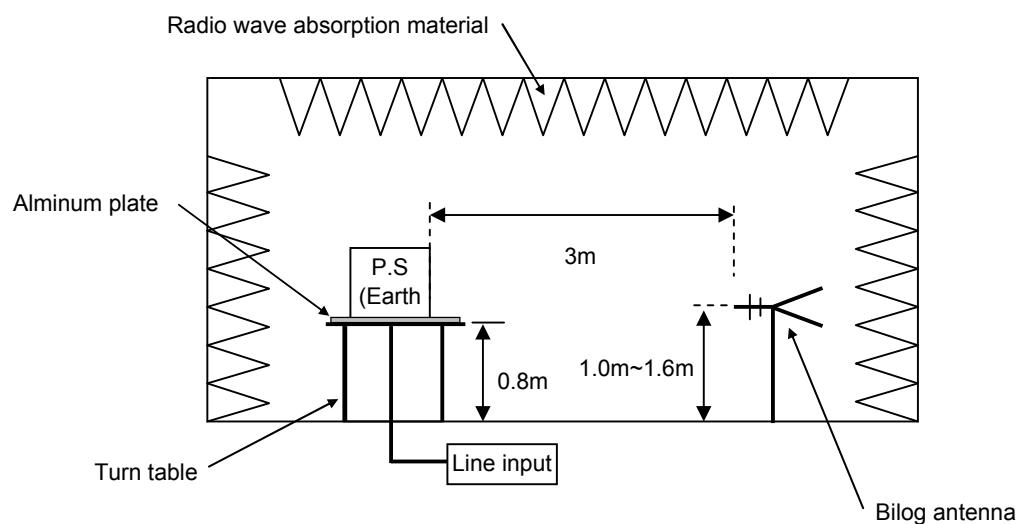
Frequency MHz	Polarization	Stability	Reading dB(uV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP			QP		QP	QP				
141.586	H	Stable	54.1	-20.1		34		40	6	Pass	146	175	
159.264	V	Stable	48.4	-20.8		27.6		40	12.4	Pass	146	268	
169.508	H	Stable	54.1	-22		32.1		40	7.9	Pass	153	176	
274.186	V	Stable	54.4	-18		36.4		47	10.6	Pass	122	56	
277.364	H	Stable	51.9	-18		33.9		47	13.1	Pass	107	348	

DATA SHEET		Date	09-Mar-10
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Uetani

1. Line conduction



2. Radiated emission



Model Name:DPG500/750

LINE CONDUCTION



○ Test circuit

C1,C2,C4 : 0.68uF 250V Film Capacitor × 2
C3 : 1.0uF 250V Film Capacitor × 2
C5 : 560uF 450V Electrolytic Capacitor
C11,C12,C13 : 2200pF Ceramic Capacitor
L1,L2 : SC-15-200(NEC TOKIN)